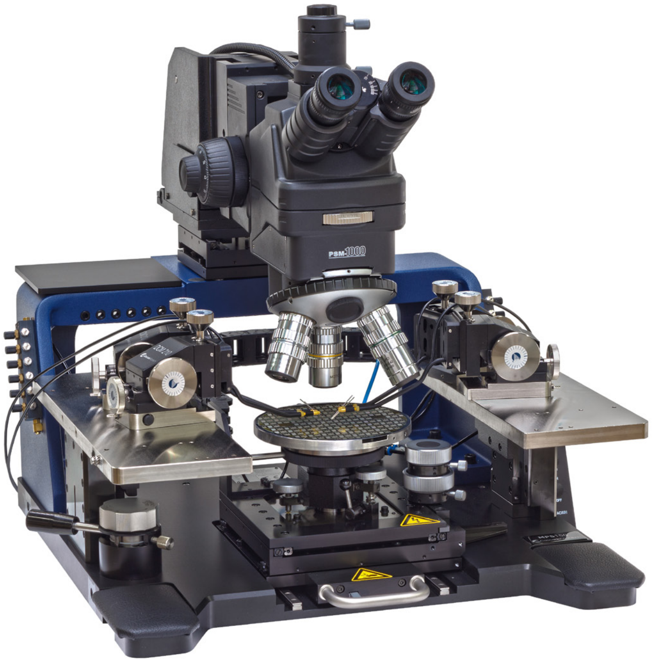
EPS150FA

A dedicated 150 mm manual probing solution for failure analysis



The EPS150FA is a dedicated probing solution that comes with everything you need to achieve accurate measurement results in the shortest time, with maximum confidence. The system incorporates best-known methods for electrical failure verification, localization and debug with the ability to probe features smaller than 1 µm.

The EPS150FA minimizes 'time-to-data' through providing flexibility to adapt from wafer-to-chip-to-package investigation in a matter of seconds.

Contact stability down to sub-µm levels is ensured through a very stable system platform design with a vibration-isolation solution to protect contact quality over measurement time. Optimized high-magnification optics on a rigid microscope bridge, backlash-free X-Y-Z movement of high-precision positioners, vacuum-operated positioner bases, and a contact separation drive with 1 µm repeatability, enable quick, precise probe placement comparable to semi-automatic systems. The EPS150FA enables simultaneous use of cantilever probe cards and individual probes for enhanced internal-node probing.

An intuitive operation workflow with pull-out chuck, single-handed chuck adjustment, and a highly-planar chuck surface and movement, ensures ease of operation for both the novice and the expert user.

Designed for upgradability and extendable with multiple options such as laser-cutting, liquid crystal thermography, and high-impedance probing, the EPS150FA system can be easily reconfigured to meet your future project requirements.

BENEFITS

Make everyone a failure analysis expert

Best-known methods for verification, localization and debug

Minimize time to data

Quickest transition from wafer, to chip, to package

Ensure contact stability down to sub-µm levels

Precise mechanics, rigid components and vibration damping design

Protect your investment for the future

Re-configure and efficiently upgrade, e.g. thermography and laser cutting

Minimize training efforts

Designed for convenience and ease of use

CascadeMicrotech®

EPS150FA

Four high-precision positioners with coaxial probe arms
- Designed for internal node probing
- Vacuum base for precise adjustment
- Compatible with PTT probes (included)

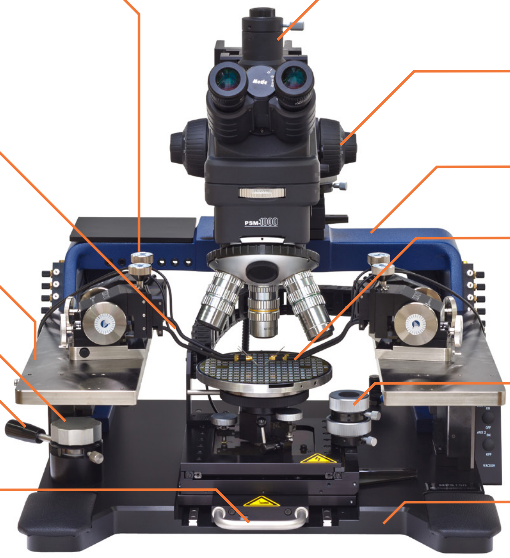
High-quality coaxial cables
- Integrated with probe arms for optimized signal path

Universal probe platen
- Rigid and stable design
- Compatible with probe card

40 mm platen drive
- Flexibility for wafer-level and package test

Unique 200 µm platen contact/separation stroke
- < ±1 µm accuracy for repeatable contact quality
- Convenient and easy to use

Chuck stage with 90 mm roll out
- Risk-free wafer loading when both probe card and positioners are used



High-resolution microscope
- Enables internal node probing on µm features
- LED illumination for excellent image contrast and long lifetime
- Compatible with laser cutter, polarizer and C-mount camera

Quick scope height adjustment
- Easy re-configuration for wafer and DUT-board applications

Stable microscope bridge
- Enables high-magnification microscopy

Coaxial chuck
- < ± 3 µm planarity for consistent overtravel across the wafer
- Supports single chip and wafers
- Designed for device biasing

Chuck X/Y movement
- Precise X/Y positioning with < 5 µm resolution
- Independent axis locks for easy linear navigation

Vibration-isolation solution
- Ensures accurate contact and minimizes pad damage

ORDERING INFORMATION

Part Number	Description
EPS150FA	150 mm manual probing solution* for failure analysis
EPS-ACC-150-PCA	Probe card adapter option
EPS-ACC-150-TC	Thermal chuck option
EPS-ACC-HDTV	Digital high-definition TV option for EPS packages containing C-mount HDTV camera, cables, power supply and 22" monitor, with crosshair overlay
EPS-ACC-TV	Analog TV option for EPS packages containing C-mount PAL TV camera, cables, power supply and 19" TV monitor
115405	Vibration isolation table VIT801
138121	SE1000 shield enclosure
119585	Adaption VIT801 to SE1000
157-842	PCB DUT board holder
157-712	TRIAX chuck

* The EPS150FA manual probing solution includes: MPS150 probe station with a 150 mm chuck stage, universal platen with 40 mm platen drive, microscope bridge with 50 mm x 50 mm movement and pneumatic tilt lift, universal scope mount with adjustable height, high-resolution microscope with 20x - 400x magnification, laser cutter ready, camera ready with LED illumination, vibration-isolation solution, universal chuck with 360° theta movement, four DPP220-V-S positioners, vacuum supply, four coaxial probe arms with 2 m cable, ten cat-whisker PTT probe tips with 0.5 µm tip radius, tweezers and all tools for setup and operation.

For more information contact us at 1-800-550-3279 (1-503-601-1000) or email sales_support@cmicro.com

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